Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/518,487	TANAKA ET AL.
Examiner	Art Unit
Suo A Waayar	3781

	SEAR	CHED	
Class	Subclass	Date	Examiner
215	379-383		
220	669,672,		
	675	6/6/2007	8V
•	to date		
215	384	10/24/2007	Ba

TNI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
215	above	10/25/2007	201
220	above	10/25/2007	311
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